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Application/Control No.	Applicant(s)/Patent under Reexamination
10/827,306	SUN ET AL.
Examiner	Art Unit
Quan-Zhen Wang	2613

	SEARCHED		
Class	Subclass	Date	Examiner
398	26,25,33, 38,45,50, 162	2/11/2007	QZW
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INTERFERENCE SEARCHED				
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